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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(213.003-D2-US)

In re Application of: **Ye et al.**

Serial No: **10/763,142**

Filed: **January 22, 2004**

Title: **Method and Apparatus for Monitoring
Integrated Circuit Fabrication**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

) Group Art Unit: **2125**

) Examiner:

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on July 30, 2004

Date

Michiko Sites
(person signing this certificate)

Michiko Sites
Signature

THIRD INFORMATION DISCLOSURE STATEMENT

Dear Sir:

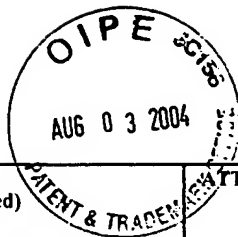
Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of each document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of these references formally of record with the initial Office Action.

Respectfully submitted,

Date: July 30, 2004

Neil A. Steinberg
Reg. No. 34,735
650-968-8079



Sheet 1 of 1

PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 213.003-D2-US	SERIAL NUMBER 10763,142
	APPLICANT(S) Ye et al.	
	FILING DATE January 22, 2004	GROUP ART UNIT 2125

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,444,637	8/1995	Smesny et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	